

1. Scope

This specification is applies to Multilayer Ceramic Chip Capacitor (MLCC) for use in electric equipment for the voltage is ranging from 100V to 5KV.

The MLCC support for Lead-Free wave and reflow soldering, and electrical characteristic and reliability are same as before. (This product compliant with the RoHS.)

2. Parts Number Code

С	1206	Х	101	К	102	Т
(1)	(2)	(3)	(4)	(5)	(6)	(7)

(1)Product

Product Code	
С	Multilayer Ceramic Chip Capacitor

(2)Chip Size

() - I		
Code	Length×Width	unit : mm(inch)
0201	0.60× 0.30	(.024× .011)
0402	1.00× 0.50	(.039× .020)
0603	1.60× 0.80	(.063× .031)
0805	2.00× 1.25	(.079× .049)
1206	3.20× 1.60	(.126× .063)
1210	3.20× 2.50	(.126× .098)
1808	4.60× 2.00	(.181× .079)
1812	4.60× 3.20	(.181× .125)
1825	4.60× 6.35	(.181× .250)
2208	5.70× 2.00	(.220× .197)
2211	5.70× 2.80	(.220× .110)
2220	5.70× 5.00	(.220× .197)
2225	5.70× 6.35	(.220× .250)

(3)Temperature Characteristics

Cod€	Γemperatur€	Temperature	Temperature
	haracteristi	Range	Coefficient
N	NPO	-55℃~+125℃	30 ppm/°C
L	SL	-30°C ~+85°C	+350~-1000ppm
X	X7R	-55℃~+125℃	± 15%
В	X5R	-55°C ~+85°C	± 15%
S	X6S	-55°C ~+105°C	± 22%
Υ	Y5V	-30°C ~+85°C	+22/-82%
Z	Z5U	+10°℃~+85°℃	+22/-56%
Е	Y5U	-30°C ~+85°C	+22/-56%

(4)Capacitance unit :pico farads(pF)

· · · -	<u> -</u>	-
Code	Nominal Capacitance (pF)	
5R0	5.0	
120	12.0	
101	100.0	
222	2,200.0	
103	10,000.0	
474	470,000.0	
105	1,000,000.0	_
106	10,000,000.0	<u> </u>

**. If there is a decimal point, it shall be expressed by an English capital letter R

(5) Capacitance Tolerance

<u> </u>		
Code	Tolerance	Nominal Capacitance
В	± 0.10 pF	Less Than 10 pF
С	± 0.25 pF	(Include 10 pF)
D	± 0.50 pF	
F	± 1.00 pF	
F	± 1.00 %	More Than 10 pF
G	± 2.00 %	
J	± 5.00 %	
K	± 10.0 %	
М	± 20.0 %	
Z	+80/-20 %	

(6)Rated Voltage

Code	Rated Voltage (Vdc)
101	100
201	200
251	250
501	500
631	630
102	1,000
202	2,000
252	2,500
302	3,000
502	5,000

(7)Tapping

Code	Type	
Т	Tape & Reel	
В	Bulk	

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3. Nominal Capacitance and Tolerance

3.1 Standard Combination of Nominal Capacitance and Tolerance

Class	Characteristic	Tolera	ance	Nominal Capacitance
I	NPO / SL	Less Then 10 pF	B (± 0.10 pF)	0.5,1,1.5,2,2.5,3
			C (± 0.25 pF)	0.5,1,1.5,2,2.5,3,3.5,4,4.5,5
			D (± 0.50 pF)	5,6,7,8,9,10
			F (± 1.00 pF)	6,7,8,9,10
		More Than 10 pF	F (±1.00 %)	E-12, E-24 series
			G (±2.00 %)	
			J (± 5.00 %)	
			K (± 10.0 %)	
П	X7R/X5R/X7E	K (± 10.0 %),	M (± 20.0 %)	E-3, E-6 series
	Y5V	M (± 20.0 %), Z	Z(+80/-20 %)	E- 3 series
	Z5U			
	Y5U			

3.2 E series(standard Number)

Standard No.	Application Capacitance											
E- 3	1.0					2	.2			4	.7	
E- 6	1.	.0	1	.5	2	.2	3	.3	4	.7	6	.8
E-12	1.0	1.2	1.5	1.8	2.2	2.7	3.3	3.9	4.7	5.6	6.8	8.2
E-24	1.0	1.2	1.5	1.8	2.2	2.7	3.3	3.9	4.7	5.6	6.8	8.2
	1.1	1.3	1.6	2.0	2.4	3.0	3.6	4.3	5.1	6.2	7.5	9.1

4. Operation Temperature Range

Class	Characteristic	Temperature Range	Reference Temp.
I	NPO	-55°C ~ +125°C	25 ℃
	SL	-25°C ~ +125°C	25 ℃
П	X7R	-55℃ ~ +125℃	25℃
	X5R	-55℃ ~ +85℃	25 ℃
	X6S	-55°C ~ +105°C	25 ℃
	Y5V	-30℃ ~ +85℃	25 ℃
	Z5U	+10°C ~ +85°C	25 ℃
	Y5U	-30℃ ~ +85℃	25 ℃
	Other	-25°C ~ +85°C	25 ℃

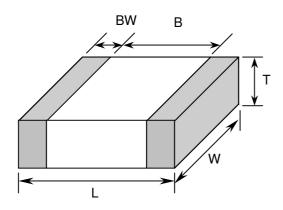
5. Storage Condition

Storage Temperature : 5 to 40° C Relative Humidity : 20 to 70 % Storage Time : 6 months max.



6. Dimensions

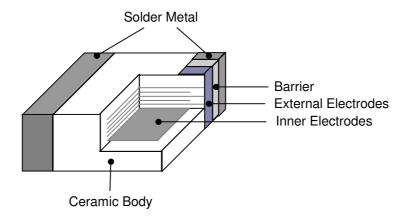
6.1 Configuration and Dimension:



Unit:mm

TYPE	L	W	Т	B (min)	BW (min)
1206	3.20± 0.30	1.60± 0.20	1.25± 0.15	1.50	0.30

6.2 Termination Type :





7. Performance

NIa	Hama	Item Specification							Toot Condition		
No.	Item						ļ		Test Condition		
1	Visua				kteric	r appearance		sual inspection			
2	Dimens			Page 3				sual inspection			
3	Insulati			$00M\Omega$ or 50				≦500V, Rated	•		
	Resista	nce	Prod	uct Whiche	ever	ls Smaller		>500V, Applied			
								arge Time: 6			
	0 "	01	NA (***)	TI 0		T :	IS 8	applied less th	an 50mA curre	ent.	
4	Capacitance	Class	vvitnin	The Spec	itiea	Tolerance	C	Class I :			
		I NPO/SL					N	NPO/SL			
		INFO/SL						Capacitance	Fraguanay	Voltage	
		Class	Within	Within The Specified Tolerance		1 -	Capacitance C≦100pF	Frequency 1MHz±10%	Voltage 1.0±0.2Vrms		
		П		·		-	C ≥ 100pr C > 100pr	1KHz±10%	1.0±0.2 VIIIIS		
								•	11(112±1076		
5	Q	Class		Than 30pF				Class			
		I		& Below: C				Frequ		Voltage	
		NPO/SL		Capacitano	e, p		ļ	X7R	1KHz±10%	1.0±0.2Vrms	
	Tan δ	Class		har.		Maximum	ļ <u>Ļ</u>	Z5U/Y5U	1KHz±10%	1.0±0.2Vrms	
		П		7R		2.5%			t temperature a ace room temp	at 150±5°C for	
	\	allia a		J/Y5U		4.0%					
6	Withstan	-		ielectric br			V < 500V : 200% Rated Voltage				
	Voltag	е	meci	nanical bre	akuu	OWII	500V ≤ V < 1000V: 150% Rated Voltage				
									Rated Voltage		
								ʻ1∼5 sec. Guri mA.	rent is limited t	o less than	
										uires immersion of	
							tn ch	ne element in a is hip surface, at vo	olation fluid preve Itage over 1000Vo	nt arcing on the	
_	Tomporaturo	Class I	Char	Temp. Ra	200	Cap. Change(%)		lass I :			
7	Temperature Capacitance	Class I		-55°C ~+1		± 30 ppm/°C			Γ2-T1)] × 100%	<i>/</i> _	
	Coefficient		SL	-30°C ~+85		+350~-1000ppm	C	lass II :	12-11)] × 1007	0	
	Coomoioni	Class		Temp. Ra		Cap. Change(%)	4	(C2-C1)/C1	× 100%		
		Ulass ∏		•	_	± 15%	T1:	,	nperature (25°	C)	
		11	Y5U	-30℃ ~+8		+22% ~-56%		: Test tempera		,	
										mperature(25°€)	
			250	+10℃~+8	35 C	+22% ~-56%	C2	:: Capacitance	at test temper	rature (T2)	
8	Adhesive S					ng shall occur on				hall be applied	
	of Termin	ation	the ter	minal elec	trode) .	fo	or 10± 1 secon	d.		
									7		
									J 501 (
									5N·f		
									ļ		
9	Resistance	Appear-	No me	echanical c	lama	ge shall be occur.	Be	nding shall be	applied to the	1.0 mm with	
		ance					1.	.0 mm/sec.	R230	1	
	Flexure	C-Meter	Capac	itance Cha	ange				11230	∠ 	
	of Substrate		Char.		Cap	o. Change				Limit	
			NPO			5.0%		<u> </u>	Meter		
			SL		<u>≦</u> ±	5.0%		←	→		
			X7R		≦ ±	12.5%		' 45±1mm	n ' 45±1mm '		
			Y5U/Z		≦ ±	30.0%					



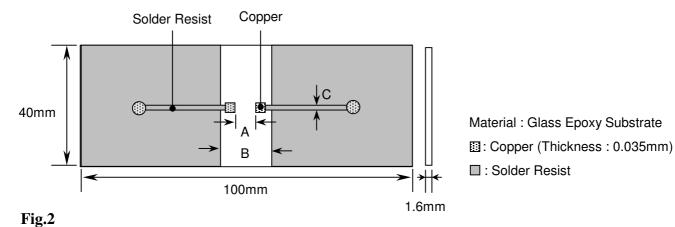
No.	Ite	m		Spec	cific	ation				Test	Condition		
10	Solder	ability	is to be		new	e terminal surface rely, so metal part dissolve.		Dip Tir Immer Solder Flux	me : { sing : : :	5 ± 0.5 se Speed : 2 H63A Rosin	: 245± 5℃ ec. 25±10% mr 0 ℃ for 10		
11	Resistance To Soldering Heat	ance Capacitance Q Class I Tan δ Class II Insulation Resistance	Class (NPO/S) Class II To sati	aracteristic I SL) X7R Z5U/Y5U sfy the spec sfy the spec	i i i i i i i i i	ge shall occur. Cap. Change Within ± 2.5% or ±0.25pFwhichever is larger of initial value Within ± 10% Within ± 20% ed initial value ed initial value ed initial value	Dip: Solder Temperature of 260±5°C Dip Time: 10 ± 1sec. Immersing Speed: 25±10% mm/s Solder: H63A Flux: Rosin Measure at room temperature after cooling Class I: 24 ± 2 Hours Class II: 48 ± 4 Hours						
12	Tempera ture Cycle	Appearance Capacitance Q Class I Tan δ Class II	Class II To sati	aracteristic I SL) X7R Z5U/Y5U sfy the spec	i i v	ge shall occur Cap. Change Within ± 2.5% or ±0.25pFwhichever is larger of initial value Within ± 7.5% Within ± 20% ed initial value ed initial value ed initial value	Capacitor shall be subjected to five cycle the temperature cycle as following: Step Temp.(°C) Time(r 1 Min Rated Temp. +0/-3 30 2 25 3		r heat treat reasure. five cycles ring: Time(min) 30 3 30 3 fter cooling	of			
13		Appearance Capacitance Q Class I Tan δ Class II Insulation Resistance	Class II More 7 30pF 8 Ch	racteristic I SL) X7R Z5U/Y5U Than 30pF: Below: Q Parar. 7R /Y5U MΩ or 50/C	W ±0 lai W Q ≥ 2	ge shall occur Cap. Change Ithin ± 5.0% or 0.5pF whichever is rger of initial value Ithin ± 15% Ithin ± 30% ≥ 350 75 +2.5×C Maximum 5.0% 5.0% whichever is			our heat e initial H	ı for			

HVC-008-0807

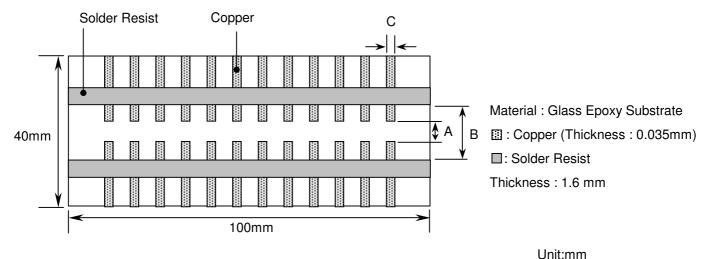
No.	Ite	m		Specific	cation		Test C	ondition		
14	High	Appear-	No mech	nanical dama	age shall occur		ass	_		
		ance					ollowing table) is app			
	Load	Capacit-		acteristic	Cap. Change	4		mperature ±3°C then		
		ance	Class I	\	Within ±3.0% or			urs at room temperature		
			(NPO/SL	-)	± 0.3pFwhichever is larger	and the initial measurement shall be conducted.				
			Class	X7R	Within ± 15%	1				
					Within ± 30%	Applied Voltage :				
		Q		an 30pF : Q			Rated Voltage	Applied Voltage		
		Class I	30pF & E	pF & Below:Q ≧ 275 + 2.5× C			V≤250Vdc	150%Rated Voltage		
		Tan δ	Char		maximum		Less Than 1KVdc	120%Rated Voltage		
		Class ∏	X7R		5.0%		More Than			
		Lee Jellee	Z5U/Y		5.0%		1KVdc(include 1KV)	100%Rated Voltage		
		Resistance	*		whichever is (C in Farad)					
		nesisiance	Silialiei.		(O III Farau)	1210/100V capacitance more than 1.0uF				
						applied voltage of 120% rated voltage				
						Temperature : max. operation temperature				
							est Time : 1000 +12/-0 urrent Applied : 50 mA			
								erature after cooling for		
						Class I : 24 ± 2 Hours Class II : 48 ± 4 Hours				
15	Vibration	Appear-	No mech	nanical dama	age shall occur		•	n P.C. Board shown in		
		ance				F	ig 2. before testing.			
		Capacit-		acteristic	Cap. Change		librata tha ganagitar u	with amplitude of 1 Emm		
		ance	Class I (NPO/SL	\	Within ± 2.5% or ± 0.25pFwhichever			vith amplitude of 1.5mm uencies from 10Hz to		
			(INFO/SL	-)	is larger		55Hz and back to 10H			
			Class	X7R	Within ± 7.5%		30112 and baok to 101	iz iii aboat 1 iiiiii.		
					Within ± 20%	Re	epeat this for 2 hours	each in 3perpendicular		
		Q			ed initial value	dir	rections.			
		Class I		•						
		Tan δ	To satisfy	y the specifi	ed initial value					
		Class II		.,						
				y the specifi	ed initial value					
		Resistance								



Fig.1
P.C. Board for Bending Strength Test



Test Substrate



			Om
Type	Α	В	С
0201	0.2	0.9	0.4
0402	0.5	1.5	0.6
0603	1.0	3.0	1.0
0805	1.2	4.0	1.6
1206	2.2	5.0	2.0
1210	2.2	5.0	2.9
1808	3.5	7.0	2.5
1812	3.5	7.0	3.7
2208	4.5	8.0	2.5
2211	4.5	8.0	3.0
2220	4.5	8.0	5.6

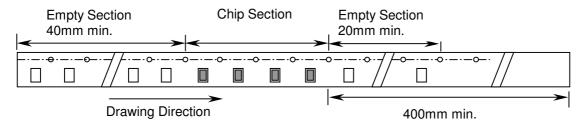


8. Packing

8.1 Bulk Packing

According to customer request.

8.2 Chip Capacitors Tape Packing



8.3 Material And Quantity

Tape	0201	0402	0603/0805	
Material	T≦0.33mm	T≦0.55mm	T≦0.90mm	T>0.90mm
Paper	15,000 pcs/Reel	10,000 pcs/Reel	4,000 pcs/Reel	NA
Plastic	NA	NA	NA	3,000 pcs/Reel

Tape		1206	1210/1808		
Material	T≦0.90mm	$0.90 \text{mm} < T \le 1.25 \text{mm}$	T>1.25mm	T≦1.25mm	T>1.25mm
Paper	4,000 pcs/Reel	NA	NA	NA	NA
Plastic	NA	3,000 pcs/Reel	2,000 pcs/Reel	3000 pcs/Reel	2000 pcs/Reel

Tape	1812/1825	/2211/2220	22	25	2208
Material	T≦2.20mm T>2.20mm		T≦2.20mm	T>2.20mm	T≦2.20mm
Paper	NA	NA	NA	NA	NA
Plastic	1000 pcs/Reel	700 pcs/Reel	1000 pcs/Reel	400 pcs/Reel	1000 pcs/Reel

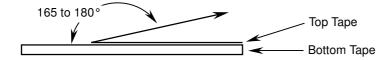
NA: Not Available

8.4 Cover Tape Reel Off Force

9.4.1 Peel-Off Force

 $5 g \cdot f \leq Peel-Off Force \leq 70 g \cdot f$

9.4.2 Measure Method





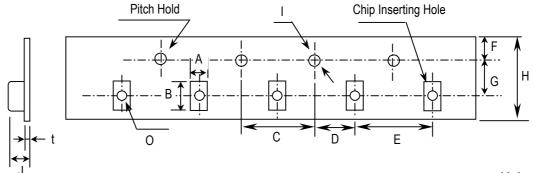
8.5 Paper Tape Pitch Hold Chip Inserting Hole G H

Unit:mm

TYPE	Α	В	С	D	E
0201	0.37± 0.1	0.67± 0.1	4.00± 0.1	2.00± 0.05	2.00± 0.1
0402	0.61± 0.1	1.20± 0.1			
0603	1.10± 0.2	1.90± 0.2			4.00± 0.1
0805	1.50± 0.2	2.30± 0.2			
1206	1.90± 0.2	3.50± 0.2			
1210	2.90± 0.2	3.60± 0.2			

TYPE	F	G	Н		t
0201	1.75± 0.10	3.50± 0.05	8.0± 0.30	φ 1.50 +0.10/-0	1.10 max.
0402					
0603					
0805					
1206					
1210					

8.6 Plastic Tape



Unit:mm

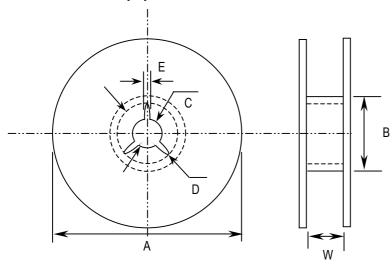
Туре	А	В	С	D	E	F
0805	1.5±0.2	2.3±0.2	4.0± 0.1	2.0± 0.05	4.0± 0.1	1.75± 0.1
1206	1.9±0.2	3.5±0.2				
1210	2.9±0.2	3.6±0.2				
1808	2.5±0.2	4.9±0.2				
1812	3.6±0.2	4.9±0.2			8.0± 0.1	
1825	6.9±0.2	4.9±0.2				
2208	2.5±0.2	6.1±0.2				
2211	3.2±0.2	6.1±0.2				
2220	5.4±0.2	6.1±0.2				
2225	6.9±0.2	6.1±0.2				



Туре	G	Н	I	J	t	0
0805	3.5± 0.05	8.0± 0.3	φ 1.5+0.1/-0	3.0 max.	0.3 max.	0.15 min.
1206						
1210						
1808	5.5± 0.05	12.0 ± 0.3		4.0 max.		
1812						
1825						
2208						
2211						
2220						
2225						

8.7 Reel Dimensions

Reel Material: Polystyrene



Unit:mm

Type	Α	В	С	D	E	W
0201	φ 382 max	arphi 50 min	φ 13± 0.5	φ 21± 0.8	2.0±0.5	10± 0.15
0402						
0603						
0805						
1206						
1210						
1808	φ 178±0.2	φ 60±0.2				13±0.3
1812						
1825						
2208						
2211						
2220						
2225						

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Precautionary Notes:

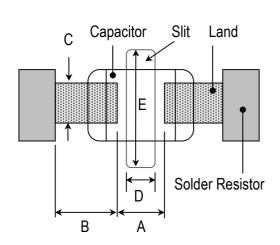
1. Storage

Store the capacitors where the temperature and relative humidity don't exceed 40 °C and 70%RH. We recommend that the capacitors be used within 6 months from the date of manufacturing. Store the products in the original package and do not open the outer wrapped, polyethylene bag, till just before usage. If it is open, seal it as soon as possible or keep it in a desiccant with a desiccation agent.

2. Construction of Board Pattern

Improper circuit layout and pad/land size may cause excessive or not enough solder amount on the PC board. Not enough solder may create weak joint, and excessive solder may increase the potential of mechanical or thermal cracks on the ceramic capacitor. Therefore we recommend the land size to be as shown in the following table:

2.1 Size and recommend land dimensions for reflow soldering .

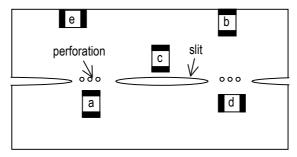


EIA Code	Chip (mm)		Land (mm)				
EIA Code	L	W	Α	В	С	D	Е
0201	0.60	0.30	0.2~0.3	0.2~0.4	0.2~0.4		
0402	1.00	0.50	0.3~0.5	0.3~0.5	0.4~0.6		1
0603	1.60	0.80	0.4~0.6	0.6~0.7	0.6~0.8		1
0805	2.00	1.25	0.7~0.9	0.6~0.8	0.8~1.1		1
1206	3.20	1.60	2.2~2.4	0.8~0.9	1.0~1.4	1.0~2.0	3.2~3.7
1210	3.20	2.50	2.2~2.4	1.0~1.2	1.8~2.3	1.0~2.0	4.1~4.6
1808	4.60	2.00	2.8~3.4	1.8~2.0	1.5~1.8	1.0~2.8	3.6~4.1
1812	4.60	3.20	2.8~3.4	1.8~2.0	2.3~3.0	1.0~2.8	4.8~5.3
1825	4.60	6.35	2.8~3.4	1.8~2.0	5.1~5.8	1.0~4.0	7.1~8.3
2208	5.70	2.00	4.0~4.6	2.0~2.2	1.5~1.8	1.0~4.0	3.6~4.1
2211	5.70	2.80	4.0~4.6	2.0~2.2	2.0~2.6	1.0~4.0	4.4~4.9
2220	5.70	5.00	4.0~4.6	2.0~2.2	3.5~4.8	1.0~4.0	6.6~7.1
2225	5.70	6.35	4.0~4.6	2.0~2.2	5.1~5.8	1.0~4.0	7.1~8.3

2.2 Mechanical strength varies according to location of chip capacitors on the P.C. board.

Design layout of components on the PC board such a way to minimize the stress imposed on the components, upon flexure of the boards in depanelization or other processes.

Component layout close to the edge of the board or the "depanelization line" is not recommended. Susceptibility to stress is in the order of: a>b>c and d>e



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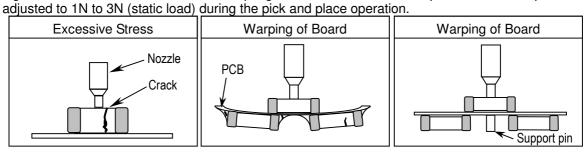


2.3 Layout Recommendation

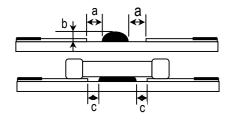
Example	Use of Common Solder Land	Solder With Chassis	Use of Common Solder Land With Other SMD
Need to Avoid	Chip Solder Adhesive PCB Solder Land	Chassis Excessive Solder a	Solder Land
Recommendation	Chip Solder Resist Adhesive PCB Solder Land	Solder Resist $\alpha > \beta$	

3. Mounting

3.1 Sometimes crack is caused by the impact load due to suction nozzle in pick and place operation. In pick and place operation, if the low dead point is too low, excessive stress is applied to component. This may cause cracks in the ceramic capacitor, therefore it is required to move low dead point of a suction nozzle to the higher level to minimize the board warp age and stress on the components. Nozzle pressure is typically



3.2 Amount of Adhesive



Example: 0805 & 1206		
а	0.2mm min.	
b	70 ~ 100 μm	
С	Do not touch the solder land	

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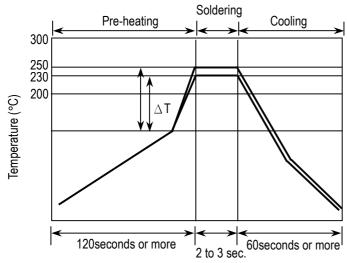


4. Soldering

4.1. Wave Soldering

Most of components are wave soldered with solder at 230 to $250\,^{\circ}$ C. Adequate care must be taken to prevent the potential of thermal cracks on the ceramic capacitors. Refer to the soldering methods below for optimum soldering benefits.

Recommend flow soldering temperature Profile



Soldering Method	Change in Temp.($^{\circ}$ C)
1206 and Under	$\Delta T \le 100 \sim 130 \text{ max}.$

To optimize the result of soldering, proper preheating is essential:

- 1) Preheat temperature is too low
 - a. Flux flows to easily
 - b. Possibility of thermal cracks
- 2) Preheat temperature is too high
 - a. Flux deteriorates even when oxide film is removed
 - b. Causes warping of circuit board
 - c. Loss of reliability in chip and other components

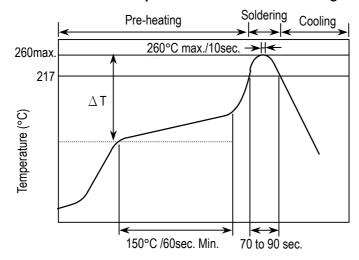
Cooling Condition:

Natural cooling using air is recommended. If the chips are dipped into a solvent for cleaning, the temperature difference (Δ T) between the solvent and the chips must be less than 100 °C.

4.2 Reflow Soldering

Preheat and gradual increase in temperature to the reflow temperature is recommended to decrease the potential of thermal crack on the components. The recommended heating rate depends on the size of component, however it should not exceed $3\,\text{C/Sec}$.

Recommend reflow profile for Lead-Free soldering temperature Profile (MIL-STD-202G #210F)



* The cycles of soldering : Twice (max.)

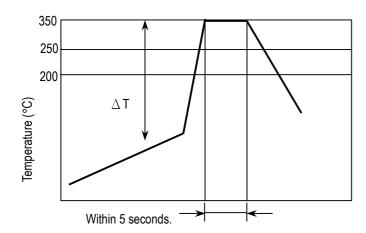
Soldering Method	Change in Temp.($^{\circ}$ C)
1206 and Under	∆T ≦ 190 °C
1210 and Over	∆T ≦ 130 °C

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4.3 Hand Soldering

Sudden temperature change in components, results in a temperature gradient recommended in the following table, and therefore may cause internal thermal cracks in the components. In general a hand soldering method is not recommended unless proper preheating and handling practices have been taken. Care must also be taken not to touch the ceramic body of the capacitor with the tip of solder Iron.



Soldering Method	Change in Temp.($^{\circ}$ C)
1206 and Under	Δ T \leq 190 $^{\circ}$ C
1210 and Over	Δ T \leq 130 $^{\circ}$ C

How to Solder Repair by Solder Iron

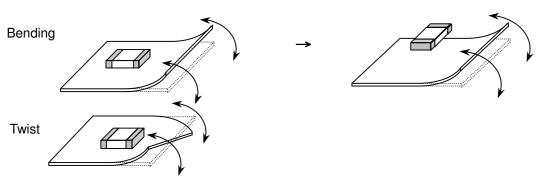
- 1) Selection of the soldering iron tip
 - The required temperature of solder iron for any type of repair depends on the type of the tip, the substrate material, and the solder land size.
- 2) recommended solder iron condition
 - a.) Preheat the substrate to $(60\,^{\circ}\text{C})$ to $120\,^{\circ}\text{C}$ to $120\,^{\circ}\text{C}$ on a hot plate. Note that due to the heat loss, the actual setting of the hot plate may have to be higher. (For example $100\,^{\circ}\text{C}$ to $150\,^{\circ}\text{C}$)
 - b.) Soldering iron power shall not exceed 30 W.
 - c.) Soldering iron tip diameter shall not exceed 3mm.
 - d.) Temperature of iron tip shall not exceed 350 ℃., and the process should be finished within 5 seconds. (refer to MIL-STD-202G)
 - f.) Do not touch the ceramic body with the tip of solder iron. Direct contact of the soldering iron tip to ceramic body may cause thermal cracks.
 - g.) After soldering operation, let the products cool down gradually in the room temperature.

5. Handling after chip mounted

5.1 Proper handling is recommended, since excessive bending and twist of the board, depends on the orientation of the chip on the board, may induce mechanical stress and cause internal crack in the capacitor.

Higher potential of crack

Lower potential of crack



5.2 There is a potential of crack if board is warped due to excessive load by check pin



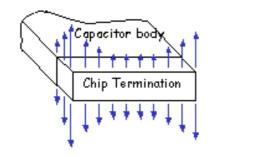
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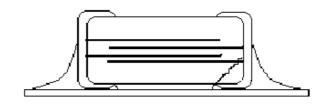


- 5.3 Mechanical stress due to warping and torsion.
 - (a) Crack occurrence ratio will be increased by manual separation.
 - (b) Crack occurrence ratio will be increased by tensile force, rather than compressive force.



Capacitor Stress Analysis



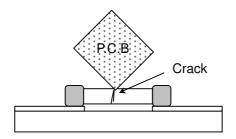


6. Handling of Loose Chip Capacitor

6.1 If dropped the chip capacitor may crack.



6.2 In piling and stacking of the P.C. boards after mounting for storage or handling, the corner of the P.C. board may hit the chip capacitor mounted on another board to cause crack.



7. Safekeeping condition and period

For safekeeping of the products, we recommend to keep the storage temperature between +5 to +40 °C and under humidity of 20 to 75% RH. The shelf life of capacitors is 6 months.

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